
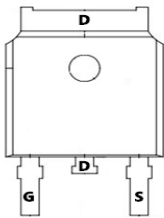
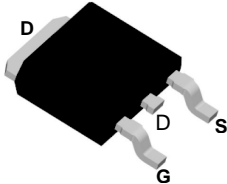
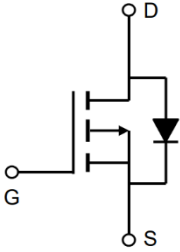


**TM80P04D**

**P-Channel Enhancement Mosfet**

<p><b>General Description</b></p> <ul style="list-style-type: none"> <li>• Low <math>R_{DS(ON)}</math></li> <li>• RoHS and Halogen-Free Compliant</li> </ul> <p><b>Applications</b></p> <ul style="list-style-type: none"> <li>• Load switch</li> <li>• PWM</li> </ul>	<p><b>General Features</b></p> <p><math>V_{DS} = -40V</math> <math>I_D = -80A</math></p> <p><math>R_{DS(ON)} = 6.4 m\Omega</math> (typ.) @ <math>V_{GS} = -10V</math></p> <p>100% UIS Tested                  100% <math>R_g</math> Tested</p> 
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**D:TO-252-3L**

Marking: 80P04

<b>Absolute Maximum Ratings (TC=25°C unless otherwise noted)</b>				
Parameter		Symbol	Value	Unit
Drain-Source Voltage		$V_{DS}$	-40	V
Gate-Source Voltage		$V_{GS}$	±20	V
Continuous Drain Current	$T_C = 25^\circ C$	$I_D$	-80	A
	$T_C = 100^\circ C$		-50.6	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	-280	A
Single Pulse Avalanche Energy <sup>2</sup>		<b>EAS</b>	101.25	mJ
Total Power Dissipation	$T_C = 25^\circ C$	<b>P<sub>d</sub></b>	81.16	W
Operating Junction and Storage Temperature Range		$T_J, T_{STG}$	-55 to 150	°C
<b>Thermal Characteristics</b>				
Parameter		Symbol	Value	Unit
Thermal Resistance from Junction-to-Ambient <sup>3</sup>		$R_{\theta JA}$	54	°C/W
Thermal Resistance from Junction-to-Case		$R_{\theta JC}$	1.54	°C/W

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Electrical Characteristics (T<sub>J</sub> = 25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
<b>Static Characteristics</b>							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-40	-	-	V	
Gate-body Leakage current	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V	T <sub>J</sub> =25°C	-	-	-1	pA
			T <sub>J</sub> =100°C	-	-	-100	
Gate-Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-1.0	-1.6	-2.5	V	
Drain-Source on-Resistance <sup>4</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = -10V, I <sub>D</sub> = -20A	-	6.4	8.1	mΩ	
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -15A	-	8.2	11		
Forward Transconductance <sup>4</sup>	g <sub>fs</sub>	V <sub>DS</sub> = -10V, I <sub>D</sub> = -20A	-	104	-	S	
<b>Dynamic Characteristics<sup>5</sup></b>							
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V, f = 1MHz	-	5295	-	pF	
Output Capacitance	C <sub>oss</sub>		-	430	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	385	-		
Gate Resistance	R <sub>g</sub>	f = 1MHz	-	4.3	-	Q	
<b>Switching Characteristics<sup>5</sup></b>							
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -20V, I <sub>D</sub> = -20A	-	110	-	nC	
Gate-Source Charge	Q <sub>gs</sub>		-	12.5	-		
Gate-Drain Charge	Q <sub>gd</sub>		-	23	-		
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = -10V, V <sub>DD</sub> = -20V, R <sub>C</sub> = 3Ω, I <sub>D</sub> = -20A	-	16.8	-	ns	
Rise Time	t <sub>r</sub>		-	10	-		
Turn-off Delay Time	t <sub>d(off)</sub>		-	65	-		
Fall Time	t <sub>f</sub>		-	17	-		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = -20A, dI/dt = 100A/μs	-	42	-	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	29	-	nC	
<b>Drain-Source Body Diode Characteristics</b>							
Diode Forward Voltage <sup>4</sup>	V <sub>SD</sub>	I <sub>S</sub> = -20A, V <sub>GS</sub> = 0V	-	-	-1.2	V	
Continuous Source Current	I <sub>S</sub>	T <sub>C</sub> = 25°C	-	-	-80	A	

Notes:

1. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub> = 150°C.
2. The EAS data shows Max. rating. The test condition is V<sub>DD</sub> = -30V, V<sub>GS</sub> = -10V, L = 0.1mH, I<sub>AS</sub> = -45A.
3. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.
4. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.
5. This value is guaranteed by design hence it is not included in the production test.

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Typical Characteristics

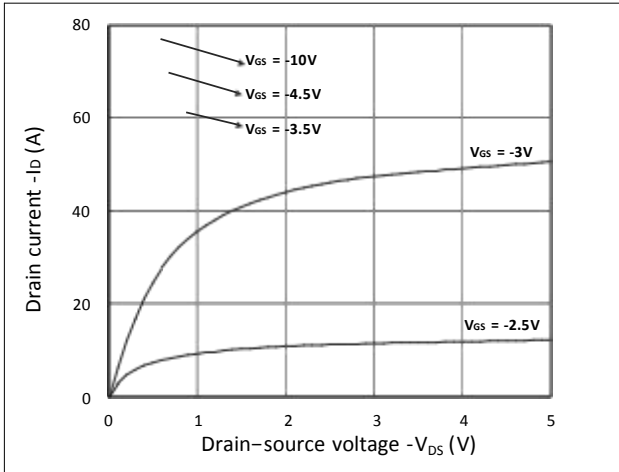


Figure 1. Output Characteristics

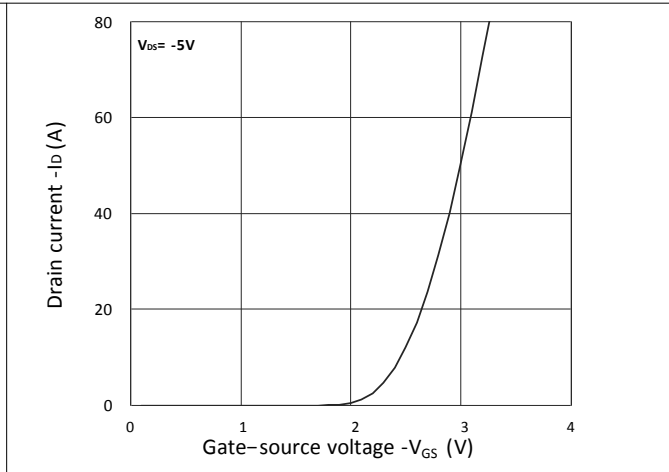


Figure 2. Transfer Characteristics

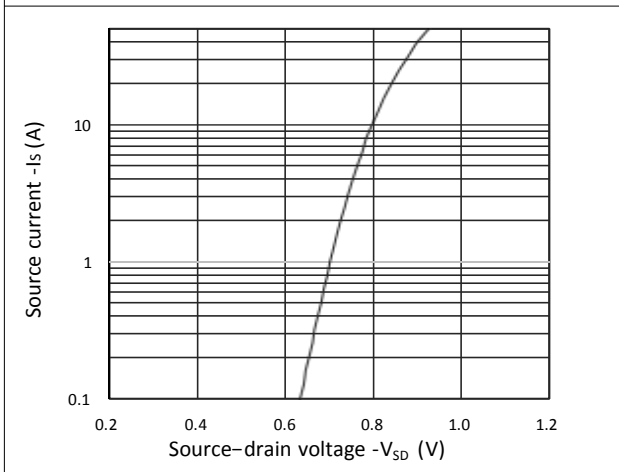


Figure 3. Forward Characteristics of Reverse

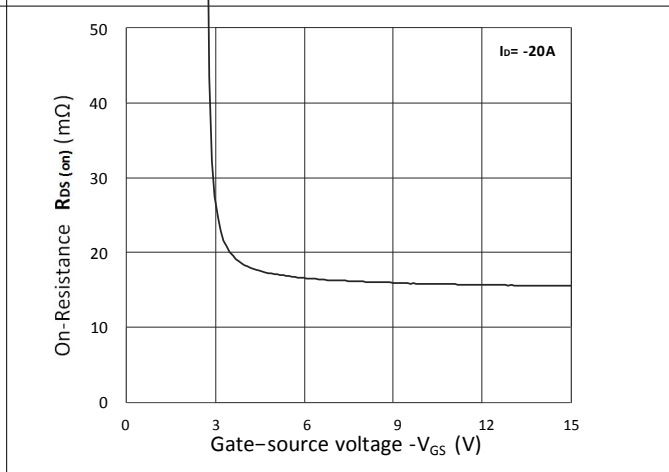


Figure 4.  $R_{DS(on)}$  vs  $V_{GS}$

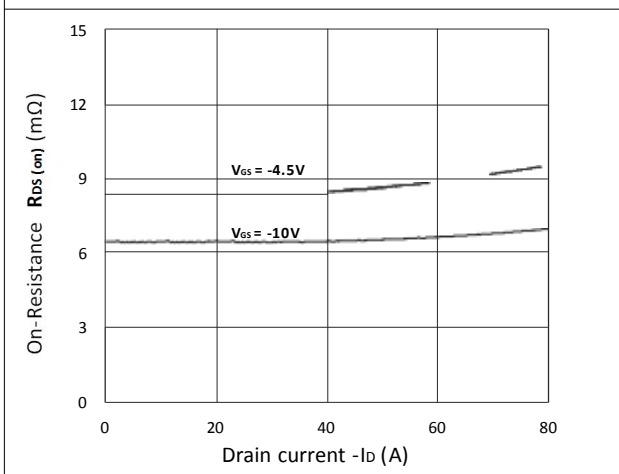


Figure 5.  $R_{DS(on)}$  vs  $I_D$

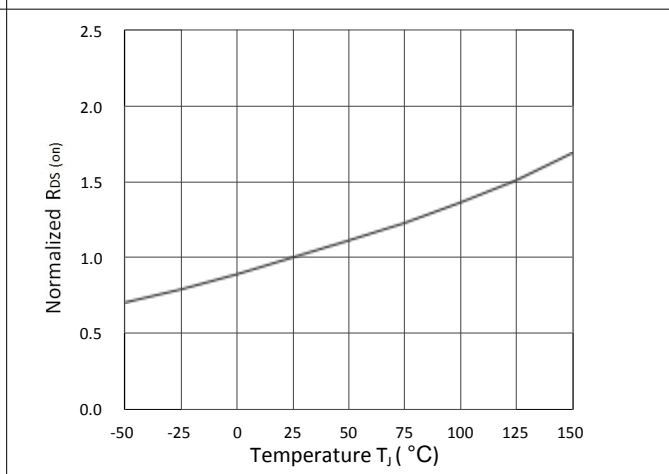


Figure 6. Normalized  $R_{DS(on)}$  vs Temperature

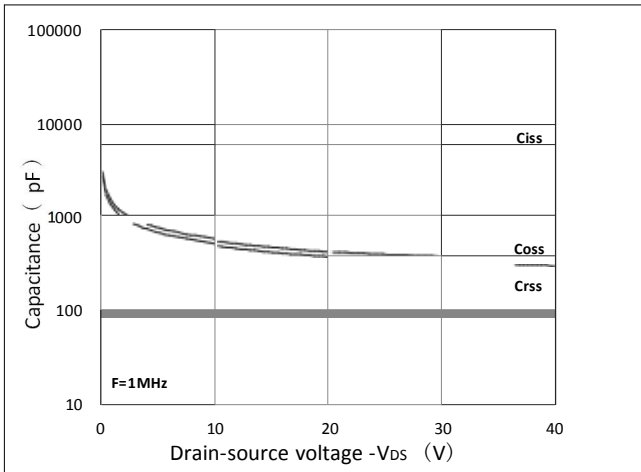


Figure 7. Capacitance Characteristics

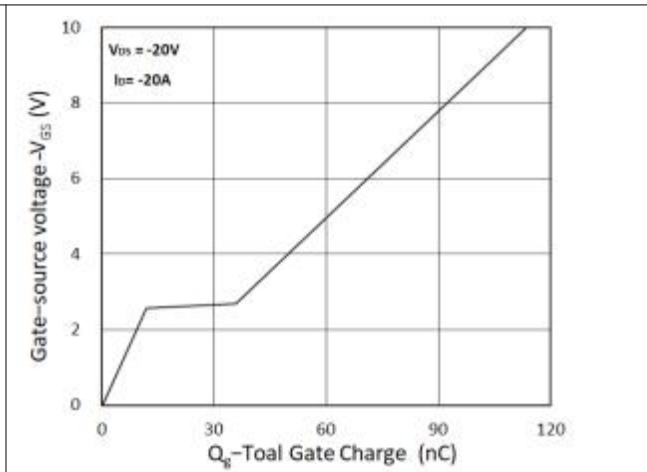


Figure 8. Gate Charge Characteristics

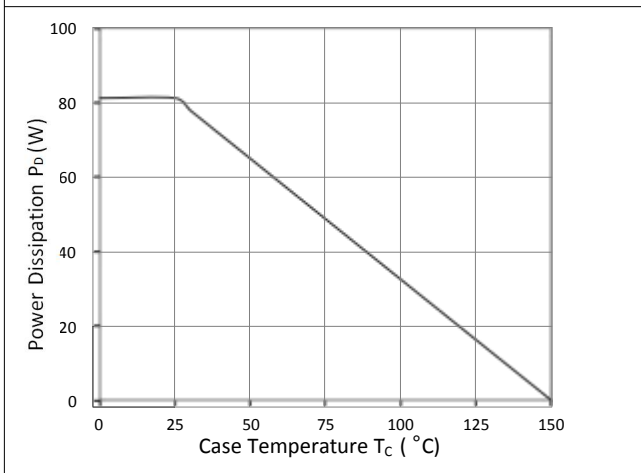


Figure 9. Power Dissipation

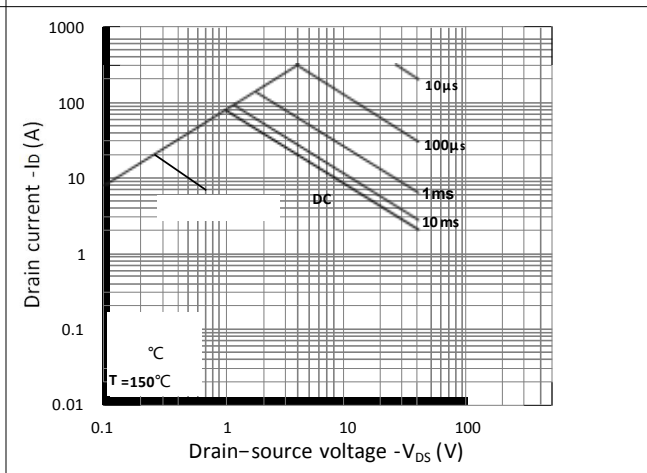


Figure 10. Safe Operating Area

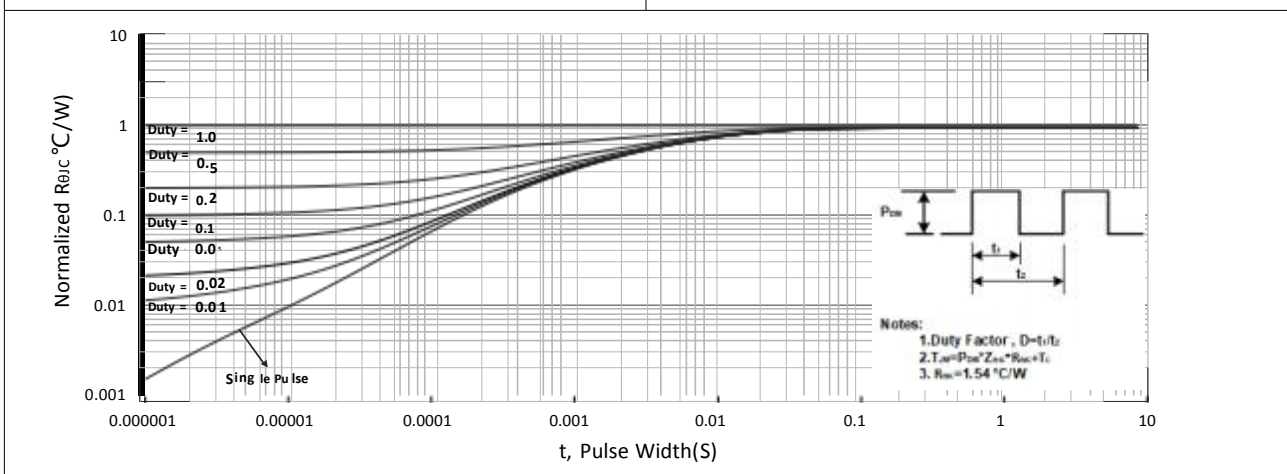


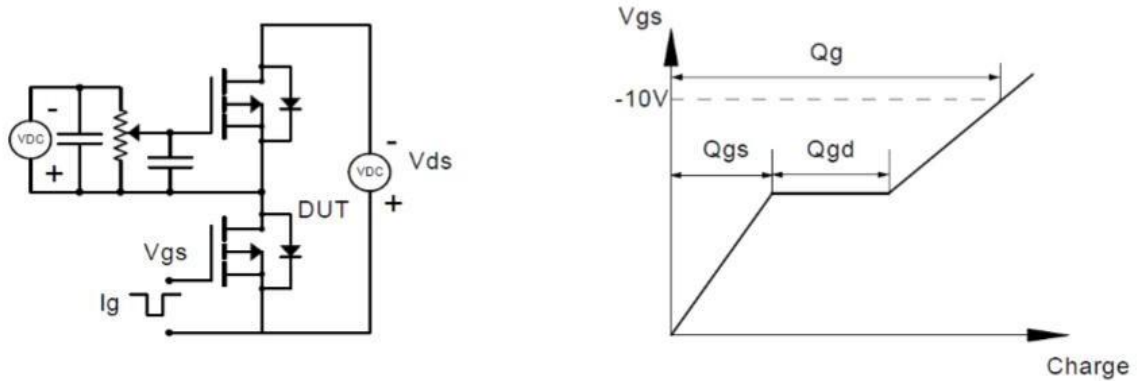
Figure 11. Normalized Maximum Transient Thermal Impedance

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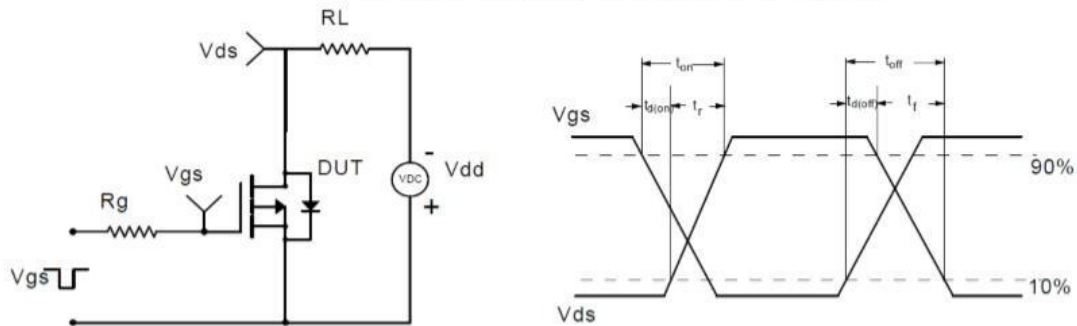
P-Channel Enhancement Mosfet

Test Circuit

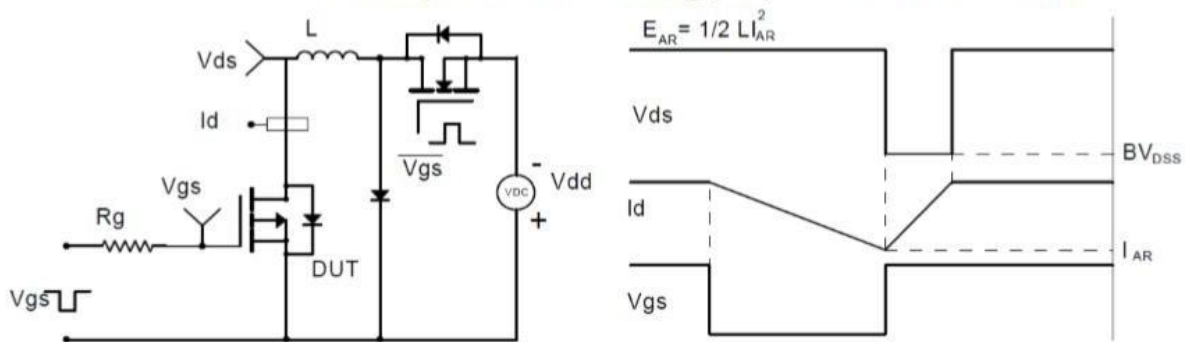
Gate Charge Test Circuit & Waveform



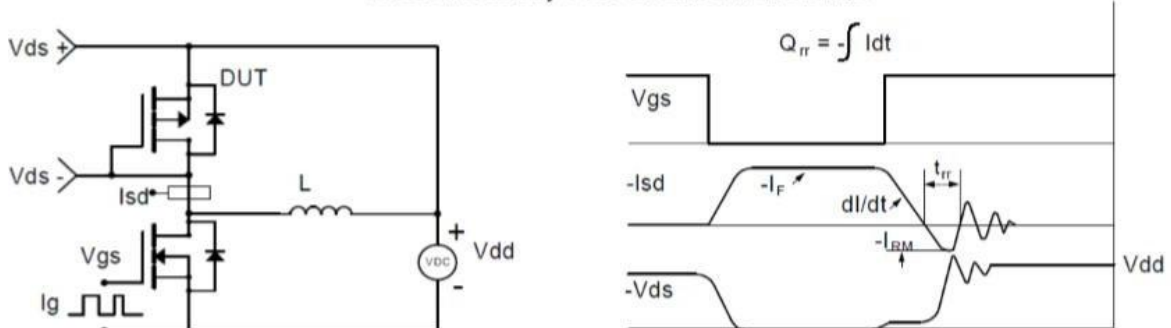
Resistive Switching Test Circuit & Waveforms



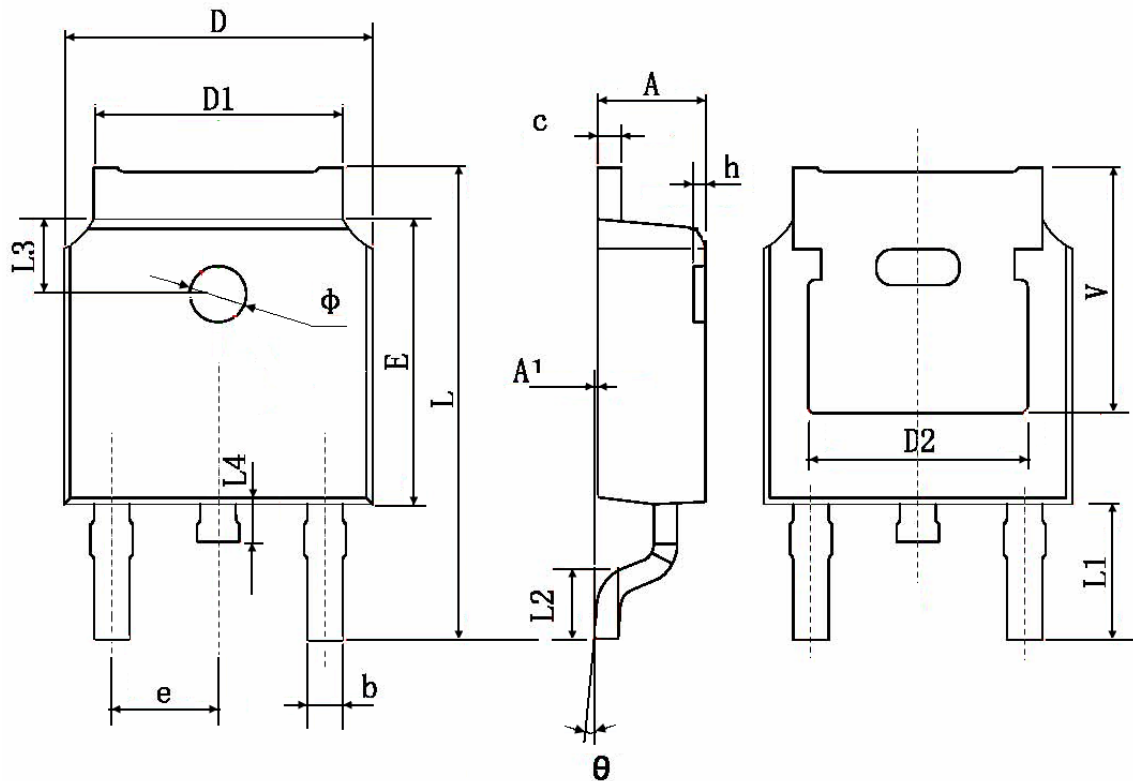
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



# Package Information:TO-252-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
phi	1.100	1.300	0.043	0.051
theta	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	